

FDW2502PZ

Dual P-Channel 2.5V Specified PowerTrench® MOSFET

General Description

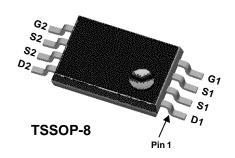
This P-Channel 2.5V specified MOSFET is a rugged gate version of Fairchild's Semiconductor's advanced PowerTrench process. It has been optimized for power management applications with a wide range of gate drive voltage (2.5V –12V).

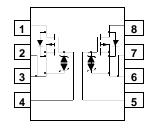
Applications

- Load switch
- Motor drive
- DC/DC conversion
- Power management

Features

- -4.4 A, -20 V. $R_{DS(ON)}$ = 0.035 Ω @ V $_{GS}$ = -4.5 V $R_{DS(ON)}$ = 0.057 Ω @ V $_{GS}$ = -2.5 V.
- Extended V_{GSS} range (±12V) for battery applications.
- ESD protection diode (note 3).
- High performance trench technology for extremely low R_{DS(ON)}.
- Low profile TSSOP-8 package.





Absolute Maximum Ratings T_A=25°C unless otherwise noted

Symbol	Parameter		Ratings	Units
V _{DSS}	Drain-Source Voltage		-20	V
V _{GSS}	Gate-Source Voltage		±12	V
I _D	Drain Current - Continuous	(Note 1a)	-4.4	А
	- Pulsed		-30	
P _D	Power Dissipation for Single Operation	(Note 1a)	1.0	W
		(Note 1b)	0.6	
T _J , T _{STG}	Operating and Storage Junction Temperature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	(Note 1a)	125	°C/W
		(Note 1b)	208]

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
2502PZ	FDW2502PZ	13"	12mm	3000 units

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Char	acteristics			I	I	
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-20			V
ΔBV DSS ΔTJ	Breakdown Voltage Temperature Coefficient	I_D = -250 μ A, Referenced to 25°C		-17		mV/°C
l _{DSS}	Zero Gate Voltage Drain Current	$V_{DS} = -16 \text{ V}, V_{GS} = 0 \text{ V}$			-1	μΑ
I _{GSSF}	Gate-Body Leakage, Forward	$V_{GS} = -12 \text{ V}, V_{DS} = 0 \text{ V}$			-10	μΑ
I _{GSSR}	Gate-Body Leakage, Reverse	$V_{GS} = 12 \text{ V}$ $V_{DS} = 0 \text{ V}$			10	μΑ
On Char	acteristics (Note 2)					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{CS}, I_D = -250 \mu A$	-0.4	-1.0	-1.5	V
ΔV GS(th) ΔT _J	Gate Threshold Voltage Temperature Coefficient	$I_D = -250 \mu A$, Referenced to 25°C		3.1		mV/°C
R _{DS(on)}	Static Drain–Source On–Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -4.4 \text{ A}$ $V_{GS} = -4.5 \text{ V}, I_D = -4.4 \text{ ,} T_{J} = 125 ^{\circ}\text{C}$ $V_{GS} = -2.5 \text{ V}, I_D = -3.3 \text{ A}$		0.028 0.039 0.043	0.035 0.056 0.057	Ω
I _{D(on)}	On–State Drain Current	$V_{GS} = -4.5 \text{ V}, V_{DS} = -5 \text{ V}$	-30			Α
g FS	Forward Transconductance	$V_{DS} = -5 \text{ V}, \qquad I_D = -4.4 \text{ A}$		17		S
Dynamic	: Characteristics					
Ciss	Input Capacitance	V 40V V 0V		1330		рF
Coss	Output Capacitance	$V_{DS} = -10 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1.0 \text{ MHz}$		552		рF
C _{rss}	Reverse Transfer Capacitance	1 = 1.0 IVII 12		153		pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time			12	25	ns
t _r	Turn-On Rise Time	$V_{DD} = -10 \text{ V}, I_{D} = -1 \text{ A},$		19	40	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = -4.5 \text{ V}, R_{GEN} = 6 \Omega$		60	100	ns
t _f	Turn-Off Fall Time	1		37	70	ns
Qg	Total Gate Charge	$V_{DS} = -5 \text{ V}, \qquad I_D = -4.4 \text{ A}, $ $V_{CS} = -4.5 \text{ V}$		14	20	nC
Q _{gs}	Gate-Source Charge			3.0		nC
Q_{gd}	Gate-Drain Charge	1.55		3.9		nC
Drain-Se	ource Diode Characteristics	and Maximum Ratings				
ls	Maximum Continuous Drain-Source				-0.83	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = -0.83 \text{ A} \text{ (Note 2)}$		-0.7	-1.2	٧

Notes

R_{0JA} is the sum of the junction-to-case and case-to-ambient thermal resistance where the case thermal reference is defined as the solder mounting surface of the drain pins. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.

a) $\rm \ R_{\theta JA}$ is 125°/W (steady state) when mounted on 1 inch² copper pad on FR-4.

b) $\rm \ R_{\rm BJA}$ is 250°/W (steady state) when mounted on minimum copper pad on FR-4.

^{2.} Pulse Test: Pulse Width < 300 μ s, Duty Cycle < 2.0.

^{3.} The diode connected between the gate and source serves only as protection against ESD. No gate overvoltage rating is implied.

Typical Characteristics

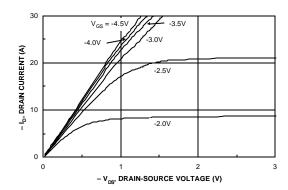


Figure 1. On-Region Characteristics.

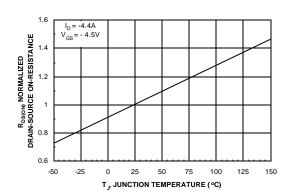


Figure 3. On-Resistance Variation with Temperature.

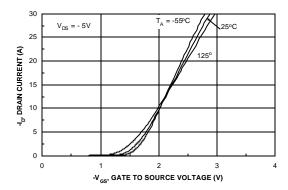


Figure 5. Transfer Characteristics.

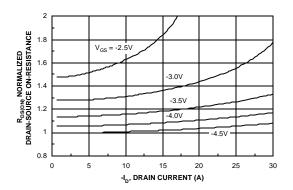


Figure 2. On-Resistance Variation with Drain Current and Gate Voltage.

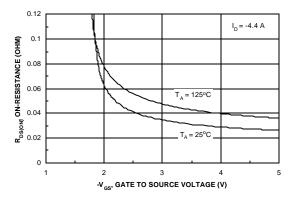


Figure 4. On-Resistance Variation with Gate-to-Source Voltage.

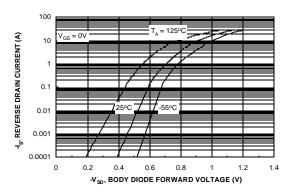
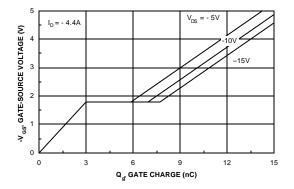


Figure 6. Body Diode Forward Voltage Variation with Source Current and Temperature.

Typical Characteristics



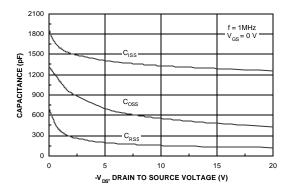


Figure 7. Gate Charge Characteristics.

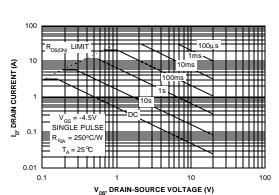


Figure 8. Capacitance Characteristics.

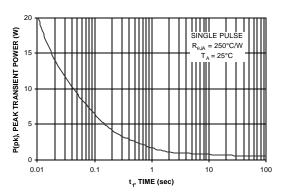


Figure 9. Maximum Safe Operating Area.



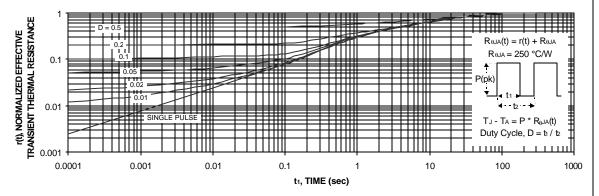


Figure 11. Transient Thermal Response Curve.

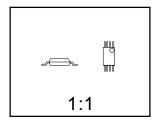
Thermal characterization performed using the conditions described in Note 1. Transient thermal response will change depending on the circuit board design.

TSSOP-8 Package Dimensions

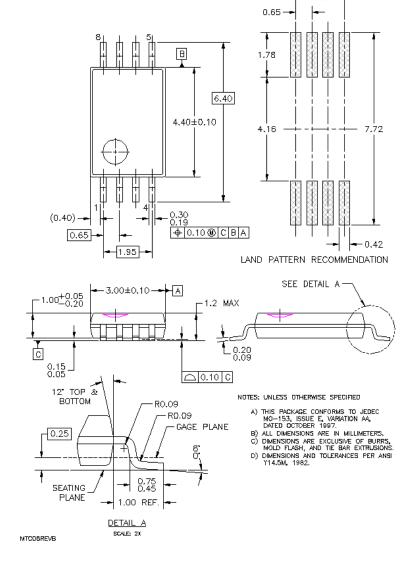


TSSOP-8 (FS PKG Code S4)





Scale 1:1 on letter size paper
Dimensions shown below are in millimeters
Part Weight per unit (gram): 0.0334



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